Standardized Testing of AC-Coupled ICs on Boards and Systems

Organized by Kenneth P. Parker, Agilent Technologies

This panel will discuss the need for a solution for testing AC-coupled nets on printed circuit boards and in systems. Traditionally, such interconnect has been DC-coupled and can thus be tested with well-known Boundary-Scan methods (EXTEST). However, the use of AC-coupling capacitors disallows DC-based techniques, giving rise to the need for an extension of Boundary-Scan into the AC realm.

The panelists will consider several questions: why is AC-coupling becoming prevalent? How has differential signaling confused this issue? Can the 1149.4 standard be used to solve this problem? Can BIST techniques solve this problem? What will it take to produce a standardized solution?

Moderator: Adam Cron, Synopsys

Panelists:

Carl Barnhart, IBM Corporation
Bill Eklow, Cisco Systems
Ken Filliter, National Semiconductor
Kenneth P. Parker, Agilent Technologies
Stephen Sunter, Logicvision